Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/509,802	HAYASHI ET AL.
F	A 1114

Examiner
/Mark L. Berch

HAYASHI ET AI	L	
Art Unit		
1624		

SEARCHED			
Class	Subclass	Date	Examiner
		·	•
4		×	
		-	
			
		·	

INTERFERENCE SEARCHED			
Class	Subclass	D <u>ate</u>	Examiner
-			
544/264 a	as PGPub	7/25/2007	MLB

(INCLUDING SEARCI		1
	DATE	EXMR
544/264 plus text term to date	7/25/2007	MLB
•		
•		
•		
•		
·		
: .		
· ·		
,		
,		
	·	